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IAM-5
Stage Mapping Grid Pattern



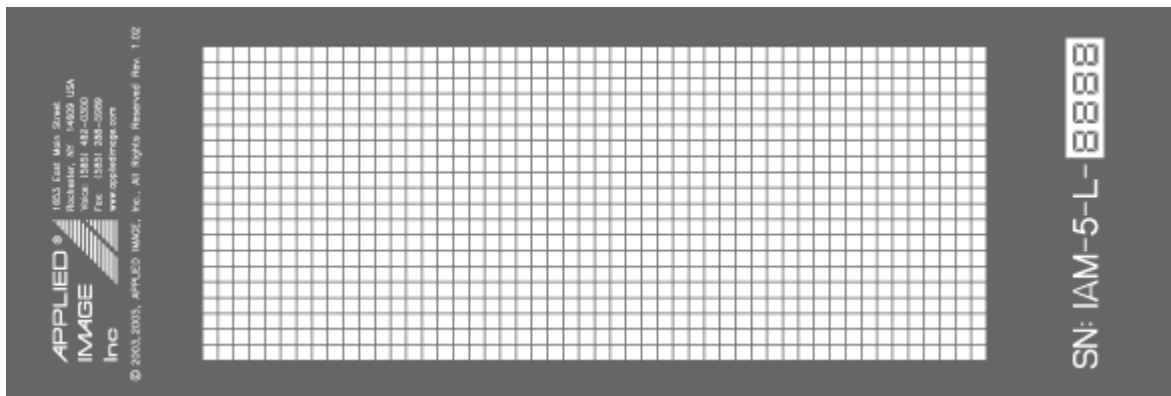
Product Specifications

Catalog Part No:

IAM-5-L-CG / IAM-5-L-OP (1000 micron line pitch)
IAM-5-M-CG / IAM-5-M-OP (200 micron line pitch)
IAM-5-S-CG / IAM-5-S-OP (10 micron line pitch)

Product Name: **Image Analysis Slide – Stage Mapping Grid Pattern**

Drawing / Photo of part:



The above image is an approximate representation of the actual product.
Specifications are subject to change without notice.

Description: This image analysis tool features a grid of opaque lines on a clear background useful for verification of magnification or comparison of different zones of an image for distortion, alignment or particle counting.

<i>Part Number</i>	<i>Substrate Type</i>	<i>Grid line pitch (microns)</i>	<i>Line width (microns)</i>
IAM-5-L-CG	Chrome on Glass	1000	20.0
IAM-5-L-OP	Chrome on Opal	1000	20.0
IAM-5-M-CG	Chrome on Glass	200	20.0
IAM-5-M-OP	Chrome on Opal	200	20.0
IAM-5-S-CG	Chrome on Glass	10	1.5
IAM-5-S-OP	Chrome on Opal	10	1.5

Grid Size: 20 x 50 mm

Image Polarity: Opaque lines on a clear field with an opaque border

Substrate Size: 25 x 75 mm

Substrate Thickness: 1.42 mm or greater

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Product Specifications

Reading Direction: Right Read Chrome Up (RRCU)

Image Placement Accuracy: 0.001mm per 100mm on glass

Feature Size Accuracy: Typical line width is 2 to 5 percent of aim

Image forming Material: Chromium and chrome oxide (gold colored)

Image Contrast or Density: Chrome transmission density is 2.6 or greater

History or Typical Use: This image analysis tool can be used for checking imaging systems for magnification, distortion, alignment or particle counting.